

Notice of References Cited	Application/Control No. 09/523,990	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Daniel I Walsh	Art Unit 2876	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,337,122	01-2002	Grigg et al.	428/195.1
	B	US-6,200,828	03-2001	Jeng et al.	438/106
	C	US-6,585,927	07-2003	Grigg et al.	264/401
	D	US-6,069,089	05-2000	Suh, Hong C.	438/707
	E	US-5,240,737	08-1993	Kawakami et al.	427/96
	F	US-4,082,873	04-1978	Williams, Frederick P.	428/42.1
	G	US-4,945,204	07-1990	Nakamura et al.	219/121.69
	H	US-5,329,090	07-1994	Woelki et al.	219/121.68
	I	US-6,601,219	07-2003	Miura et al.	716/1
	J	US-6,121,574	09-2000	Xu, Feng-Yu	219/121.69
	K	US-6,585,927	07-2003	Grigg et al.	264/401
	L	US-4,585,931	04-1986	Duncan et al.	235/462.14
	M	US-5,357,077	10-1994	Tsuruta, Hisayuki	219/121.68

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.